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CEBE Subproject P2

Verification, test and fault diagnosis

Jaan Raik

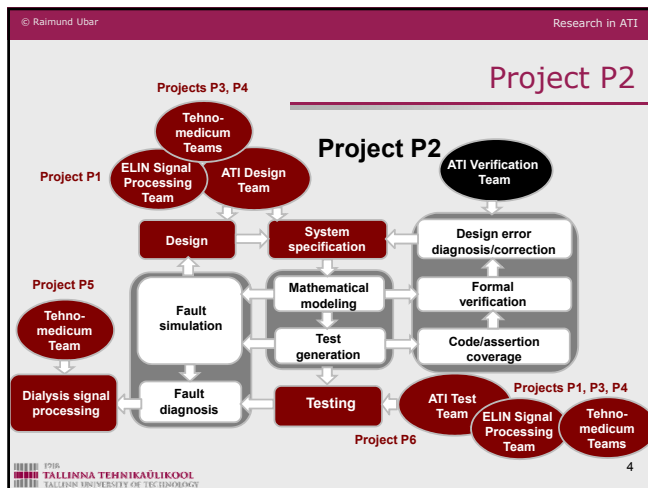
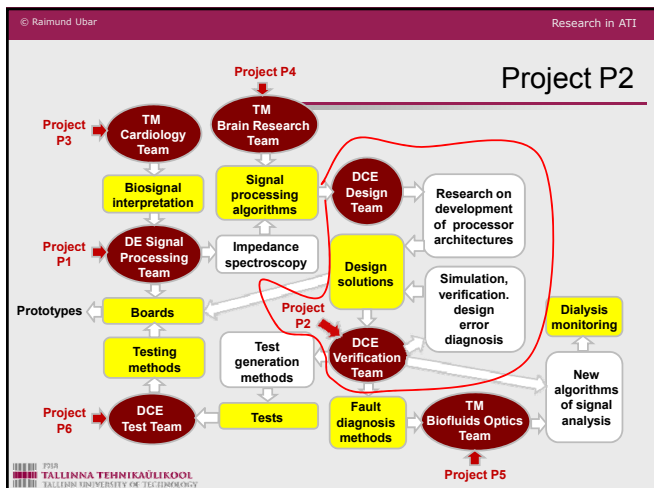
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Verification, test and fault diagnosis

- ✓ The role of subproject P2 in CEBE
- ✓ Research actions
 - Diagnostic modeling
 - Advanced fault simulation
 - Verification and diagnosis
- ✓ Tool-base developed in project P2
- ✓ FP7 STREP DIAMOND
- ✓ Conclusions, future plans

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Project P2

- ✓ **Verification, test generation and fault diagnosis**

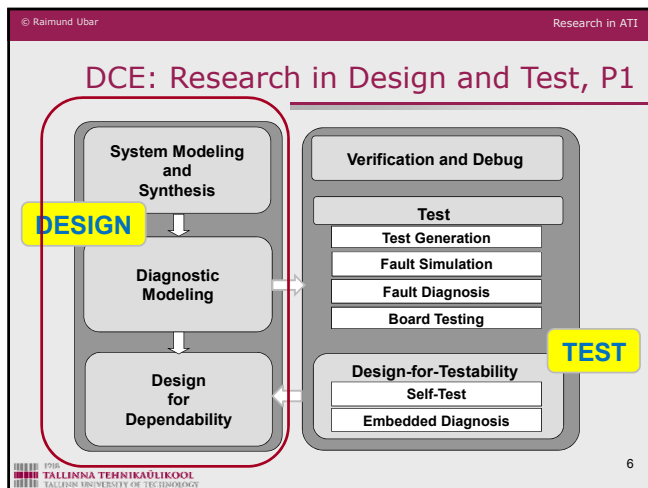
DCE Design Team:

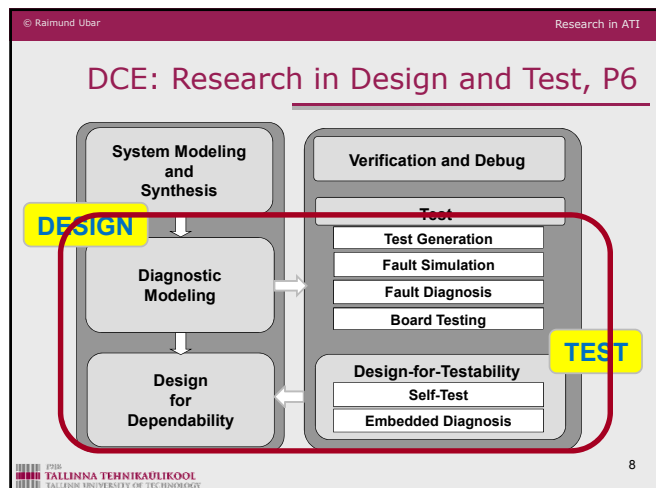
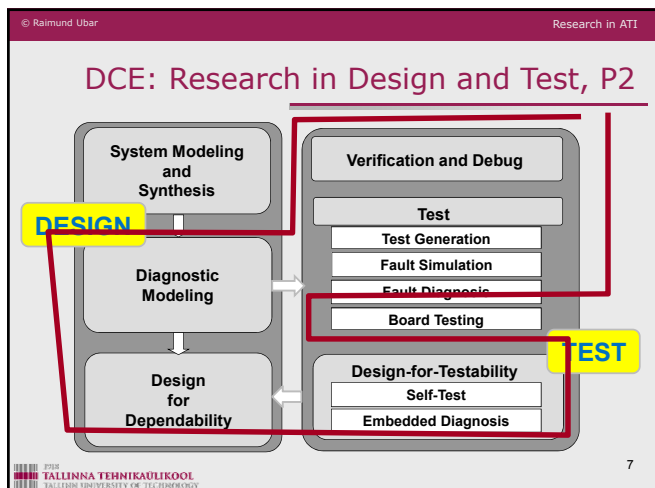
- Architectures and methods to design application specific processors for signal processing used in biomedical applications

Goals for DCE Verification Team:

- Methods for verification, self-testing, fault diagnosis and debugging of digital systems with special attention to design of dependable application specific signal processors
- Redesign of given structures for testability and self-test

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Diagnostic modeling

- ✓ Modeling of digital systems
 - A canonical form for high-level decision diagrams (HLDD) using characteristic polynomials was developed to represent RTL systems
 - It allows fast proof of equivalence of two different HLDDs.
 - The method is a new possibility for formal verification of digital systems and has high potentials to improve the efficiency of detecting design errors in design

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Formal Design Verification with DDs

A digital system can be represented by Decision Diagrams

Two DDs are equivalent. One is derived from another by equivalent transformations

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Diagnostic modeling

- ✓ New class of BDDs – SSMIBDD
 - Allows a significant reduction of the structural BDD model complexity
 - Leads to decreasing of memory requirements
 - Helps to increase the speed of logic simulation
- ✓ Fault collapsing techniques
 - The SSMIBDD based new fault collapsing method has the linear complexity and is more efficient than other structural fault collapsing methods

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Decision Diagrams

Structurally Synthesized Binary Decision Diagrams

Fault collapsing:
From 84 faults to 36 faults
Efficient effect-cause analysis

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Test generation

- ✓ Fault simulation
 - A new critical path tracing method which allows the first time to calculate the sets of detected faults in parallel for many test patterns
 - The method was extended for two general fault classes: conditional stuck-at and X-faults
- ✓ High-level test generation
 - A RTL ATPG implementing a constraint solver was developed enabling test of hard-to-test sequential designs

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Very Fast Fault Simulation

Methods and algorithms:

- ✓ Sequential
- ✓ Parallel
- ✓ Deductive
- ✓ Critical path analysis
- ✓ **Parallel critical path analysis (TUT)**

Our method increased the simulation speed compared to **Mentor Graphics and Synopsys**, in average **3-9 times** [DATE'10]

Usage: design, verification, test synthesis, test quality evaluation, fault diagnosis, fault tolerance analysis, ...

$e(i,j) = 1$ if fault R_i is detectable by test vector T_j

Fault table

$e(i,j) \in \{0,1\}$

Faults R_i

Test vectors T_j

Our method

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Extended Fault Simulation

Extensions of the parallel critical path tracing for two large general fault classes for modeling physical defects:

Defect

Multiple fault

Resistive bridge fault

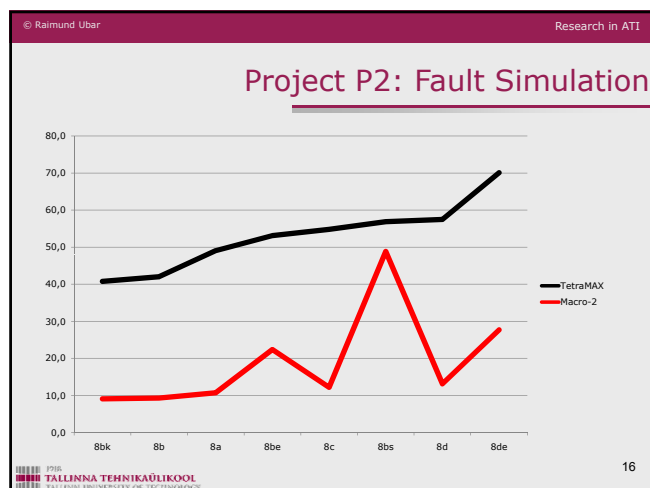
SAF

Conditional fault
Pattern fault
Constrained SAF
Single faulty signal

X-fault
Byzantine fault
Bridges
Stuck-opens
Multiple faulty signal

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Verification and diagnosis

- ✓ Verification and debug:
 - Test, verification and debug tools were integrated into a system called APRICOT
 - The tools run on a uniform design model based on high-level decision diagrams.
 - The functionality includes currently
 - test generation,
 - code coverage analysis,
 - assertion-checking,
 - mutation analysis and
 - design error diagnosis

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Verification and diagnosis

- ✓ Logic simulation
 - A simulator developed for the design navigation tool ZamiaCAD in co-operation with IBM Germany (Dr. R. Dorsch)
- ✓ Fault diagnosis
 - A novel hierarchical approach for the macro level cause-effect physical defect diagnosis in digital circuits was developed

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Design error diagnosis experiment

Design	success rate, # detected functions		average resolution, # suspects		worst resolution, # suspects	
	step1	step2	step1	step2	step1	step2
<i>gcd</i>	2/2	2/2	3	1	3	1
<i>diffeq</i>	8/8	8/8	3.3	1.9	5.6	2.8
<i>risc</i>	16/16	13/16	7.6	1.4	11.6	2.3
<i>crc</i>	25/25	20/25	17.3	2.4	21	7

Step1: Critical path tracing of mismatched outputs
 Step2: Ratio Failed/Passed backtrace cones

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Fault Diagnosis at the Block Level

Network of blocks:

Suspected defective macros: F1, F3, F6

Test results:

Test #	1	2	3	4	5	6	7	8
1	1	1	1	1	1	1	1	1
2	1	1	1	1	1	1	1	1
3	1	1	1	1	1	1	1	1
4	1	1	1	1	1	1	1	1
5	1	1	1	1	1	1	1	1
6	1	1	1	1	1	1	1	1
7	1	1	1	1	1	1	1	1
8	1	1	1	1	1	1	1	1

Conditions:

- T1: 01101 Failed
- T3: 11000 Passed
- T4: 01011 Passed

Observed SAF: F3, F6

Conditions:

- T1: 01101 Failed
- T3: 11000 Passed
- T4: 01101 Passed

Observed SAF: F6

Legend: Failed (red), Passed (green), Suspected (red), Not suspected (green)

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Fault-Model Free Fault Diagnosis

Combined cause-effect and effect-cause diagnosis

1) Cause-Effect Fault Diagnosis
 Suspected faulty area is located

2) Effect-Cause Fault Diagnosis
 Faulty block is located in the suspected faulty area

3) Fault Reasoning
 Failing test patterns are mapped into the suspected defect or into a set of suspected defects in the faulty block

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CEBE Tool-Base

Tools for test and verification

- APRICOT:** dynamic verification tools. (Assertion checking, mutation analysis, code coverage analysis, design-error correction).
- ZamiaCAD:** A debug and design exploration tool developed in cooperation with IBM Germany
- FOReNSiC:** Formal Repair Engine for Simple C, co-developed with University of Bremen and TU Graz.
- Ultra-fast fault simulator**
 SSBDD-based parallel critical path tracing fault simulator exceeds in speed commercial fault simulators
- TURBO TESTER:** a set of test tools for logic-level
- DECIDER:** very high-speed RTL test generation explained by the efficient DD-based algorithms and by the hierarchical approach
- DOT:** Defect-oriented deterministic test generator

Research environment (side effect)

- Tools and converters
- DEFSIM** - environment for investigation of defects
- E-learning software

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ZamiaCAD: An IDE for HW Design

- ✓ ZamiaCAD is an Eclipse-based development environment for hardware designs
- ✓ Design entry
- ✓ Analysis
- ✓ Navigation
- ✓ Simulation
- ✓ Scalable!
- ✓ Co-operation with IBM Germany, R. Dorsch

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APRICOT: Design Verification

Extensions of BDD ⇒ HLDD ⇒ THLDD

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Forensic – design error diagnosis for C

- ✓ FoReNSiC – *Formal Repair Engine for Simple C*
- ✓ Idea by TUG, UNIB and TUT at DATE'10
- ✓ Front-end converting simple C descriptions to flowchart model completed
- ✓ Available and open to partners at:
<https://collaboration.iaik.tugraz.at/wsvn/scos-diamond/tools/forensic>

DIAMOND Technical Meeting, Haifa, Israel, Oct. 4, 2010

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Forensic diagnosis flow

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Turbo Tester tools

Logic Level CAD Turbo Tester

Levels:
Gate
BDD

Methods:
Deterministic
Random
Genetic

Design types:
Combinational
Sequential

Wide range of easy-to-use test tools
Design interfaces to all major CAD systems

Licensed to 110+ institutions in 45+ countries!

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E-Learning Software

Software for classroom, home, labs and exams

Logic level diagnostics

System level test & DFT

Boundary Scan

Data path

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Remote Research Lab

- ✓ **DefSim** - an integrated measurement environment for physical defect study in CMOS circuits.
- ✓ **TurboTester** – a research and training toolkit with extensive set of tools for digital test and design for testability
- ✓ **Web-based** runtime interface for remote access to our tools
- ✓ **Java applets** – illustrative e-learning software written specifically for the web

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DIAMOND project

- ✓ FP7-2009-IST-4-248613 DIAMOND - *Diagnosis, Error Modelling and Correction for Reliable Systems Design*
- ✓ Start January 2010; total budget 3.8M € (EU contribution 2.9M €); 462.5 PM

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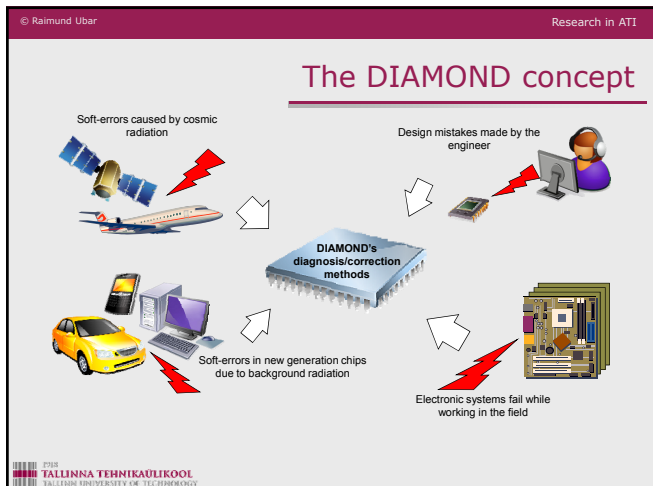
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Status and future plans

- ✓ Benchmarks for evaluating the methods on medical application created
- ✓ Test generation and fault simulation tasks performed
- ✓ Research on BIST and debug methods ongoing
- ✓ Interdisciplinary research results planned in the future with CEBE teams

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